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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application of :
Takashi NIWA et al. :
Serial No. 09/740,664 :
Filed: December 19, 2000 :
For: NEAR-FIELD OPTICAL PROBE :
AND MANUFACTURING METHOD :
FOR SAME, AND NEAR-FIELD :
OPTICAL APPARATUS USING :
THE NEAR-FIELD PROBE : Docket No. S004-4168
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COMMISSIONER OF PATENTS AND TRADEMARKS
Washington, DC 20231

PRELIMINARY AMENDMENT

S I R:

In order to place this application in better
condition for a complete examination on the merits, applicants
preliminarily amend their application as follows:

IN THE SPECIFICATION:

Please replace the paragraph beginning at page 1, line 19,
with the following rewritten paragraph:

A/ ~~A~~ scanning-type near-field atomic microscope has
also been proposed which uses an optical fiber probe formed in
a hook form as a cantilever for an atomic force microscope

02/20/2002 CV0111

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MAILING CERTIFICATE ON
LAST PAGE